

## **Era of Intelligent Power Delivery**

Mandy Pant & Bill Bowhill Nov 2012



Intel and the Intel logo are trademarks or registered trademarks of Intel Corporation or its subsidiaries in the United States and other countries. Other names and brands may be claimed as the property of others. All products, dates, and figures are preliminary and are subject to change without any notice.

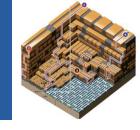
© 2012, Intel Corporation



### Outline

- Power Delivery Today
- Current Trends Challenging Power Delivery
- Opportunities
- Summary



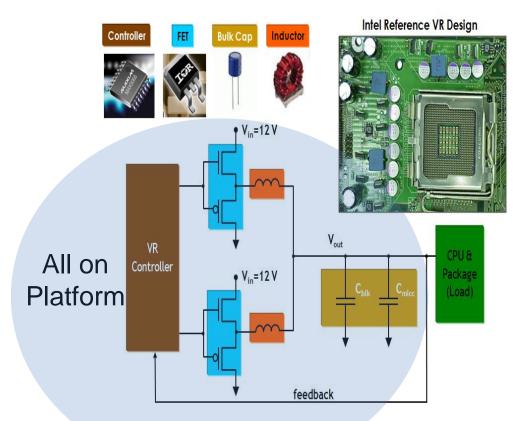


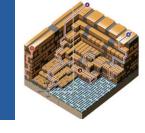
## (intel)

#### **Power Delivery Today**

#### "Big Iron Solutions"

- Platform level VR power delivery
  - VR on motherboard with switching FETs, inductors to reduce ripple and capacitors to control droop, low resistance path to socket and minimal communication with load die
- Metal Interconnect layers
  - Top level metal layers dedicated to power
  - Dedicated power and ground tracks on every metal layer
- On-die device decap
  - Decap placement opportunistic/focused budgeting in I/O
- Capacitors
  - Several arrays of capacitors on the motherboard and package

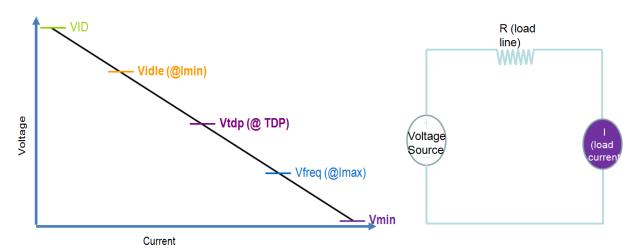


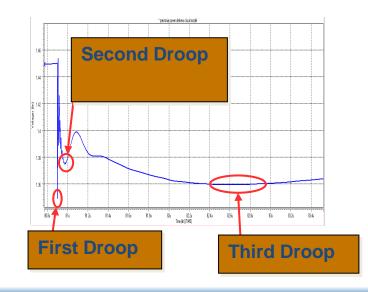


#### **Power Delivery Today**

### Mitigation of non-ideal power delivery

- Load Line
  - Outcome of power delivery impedance
  - Triple operating voltage constraints
    - Idle (Imin) conditions: Top of loadline
    - Power Virus (Imax) conditions: Bottom of loadline
    - TDP conditions: somewhere along loadline
  - Active Voltage Positioning (AVP) to minimize power impact on load
    - Associated with 3<sup>rd</sup> droop
  - System exposed to "Excess" first droop
- Droop mitigation mechanisms
  - AFS
  - DAF





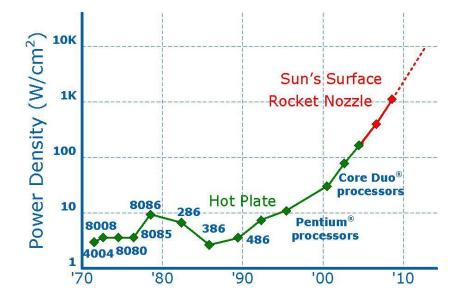
# (intel)

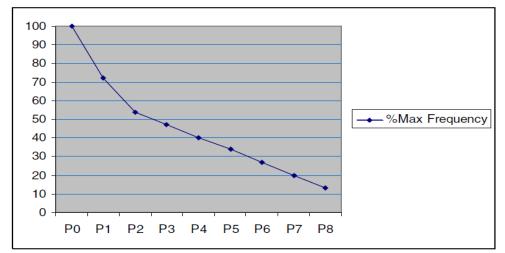
#### Power Delivery



#### **Power Delivery Today**

- Hit Power Wall
  - Increasing performance while operating within Power limits
- Response to power wall
  - Dynamic power = a.f\* C \*V<sup>2\*</sup> f
  - Decreased Cdyn, lowered V and slowed chip down
  - Used clock-gating to reduce AF
  - Focused on Pipelined optimizations so all circuits run at ideal V/F – balanced pipeline
     Note: continued lowering of V without improving power delivery can negate gains
- P (Performance)-states
  - P-states enabled CPU cores to move along the V/F curve for optimizing power efficency





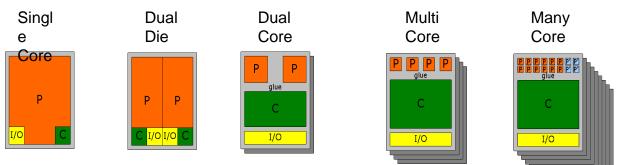
**P-state CPU frequencies** 



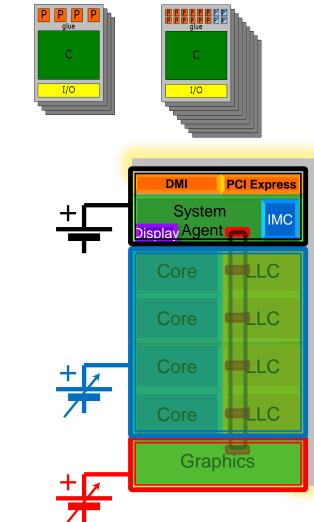


#### **Power Delivery Today**

- Response to power wall
  - TM1/TM2
    - Thermal solutions driving initial challenges
  - Multiple cores
  - Multiple voltage domains
  - Die level Power gates which enabled dynamic ON/OFF

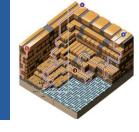


#### **Core proliferation**



#### Power-gating on Intel's SandyBridge processor

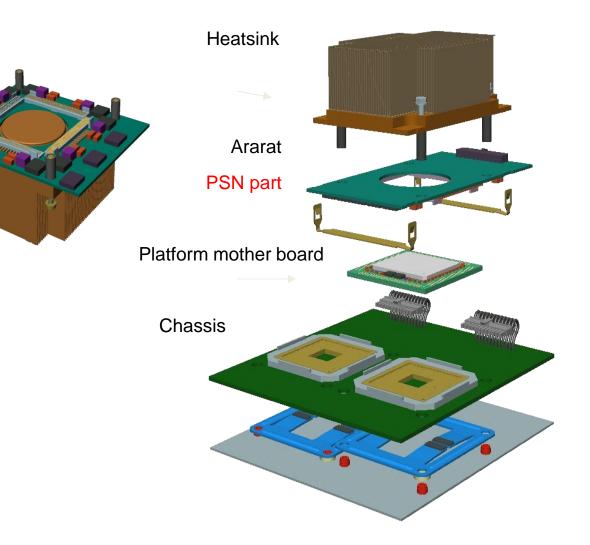






#### **Power Delivery Today**

- Local VRs, more VRs and per core pair VID
  - Availability of Ararat on Poulson
    - Enables power and performance optimization in light of increased variation
    - Ref: New Itanium for
      32nm and Beyond (MPR
      report March 2011)









- Some technology trends
  - Transistor density  $\uparrow$
  - Current density  $\uparrow$
  - − Iccmax ↑
  - − Iccstep ↑
  - Vmin↓
  - Vmax  $\downarrow$
  - Bump pitch scaling : slow
  - − Die size ↑
  - Metal stack↑
  - Interconnect wire width  $\downarrow$

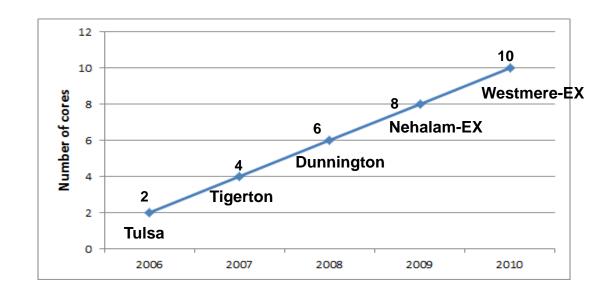


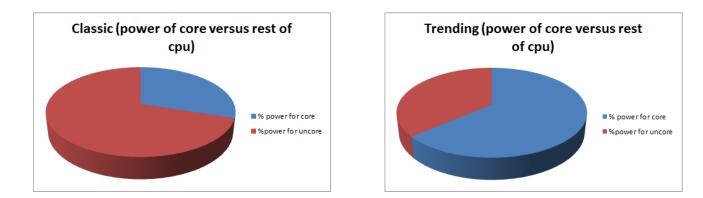




#### **Current Trends Challenging Power Delivery**

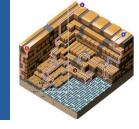
- Increasing core count for microprocessors at power limited scaling
  - Maximizing throughput under power budget → increasing number of cores
  - Close to Vmin operation for Power efficiency
    - Increased sensitivity to droop
  - % of chip power reserved for cores increasing



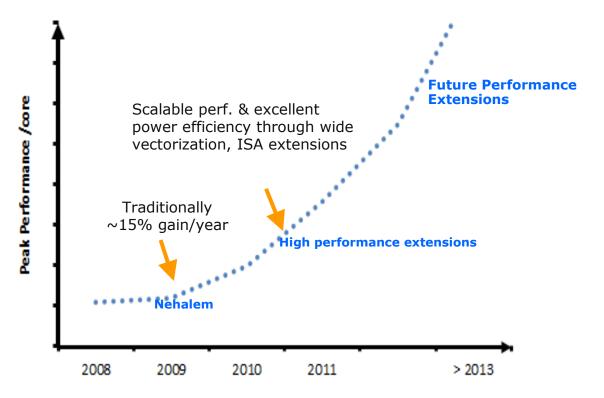


(inte



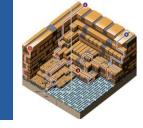


- New core vectorized instructions for performance improvement:
  - Suitable for floating point-intensive calculations in multimedia, scientific and financial applications (integer operations expected in later extensions)
  - Increases parallelism and throughput in floating point SIMD calculations
  - Reduces register load due to the non-destructive instructions



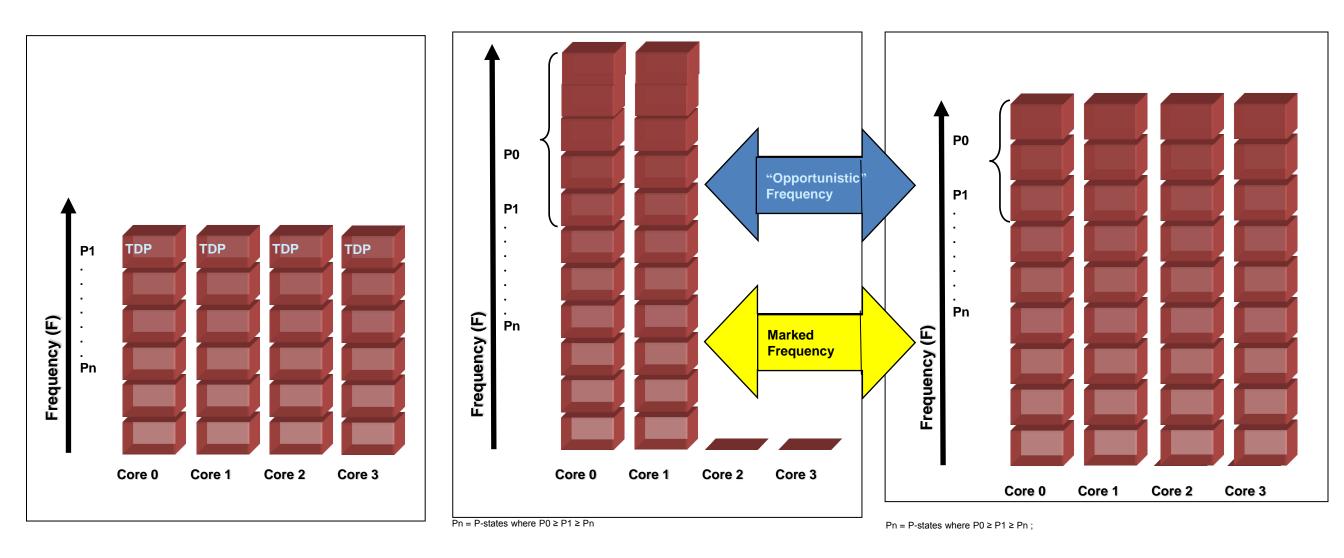






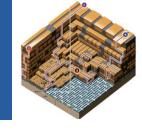
#### **Current Trends Challenging Power Delivery**

Turbo 1.0 and Turbo 2.0 for opportunistic performance improvement



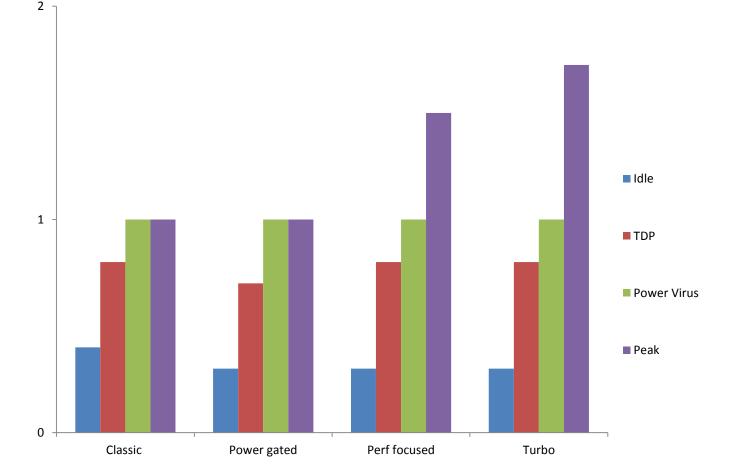




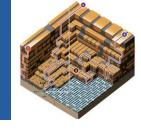


- Dynamic range of core increasing due to
  - Vectorized instructions
  - Turbo

- % of chip subject to dynamic swings increasing dramatically due to
  - Vectorized instructions
  - Turbo
  - increased number of cores

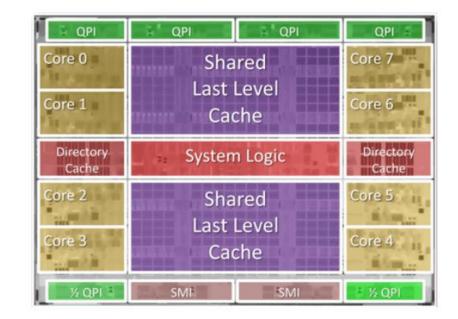






#### **Current Trends Challenging Power Delivery**

- Voltage domain proliferation to minimize power consumption
  - Dividing up power delivery resources to independently service each domain
  - Need for adequate decoupling for each domain
  - Leading to multiple clocking domains
  - Boundary latency issues
  - Requirement for increased circuitry
    - low power and variation-robust



8 core Intel PSN IPF microprocessor with 10+ voltage domains



# (intel)

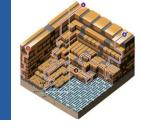
#### **Power Delivery**



- Improved User Experience
  - Requirement for AOAC
  - Extended battery life on mobile devices
    - Low leakage critical
  - CPU cores needs to turn on and respond to changing workloads seamlessly



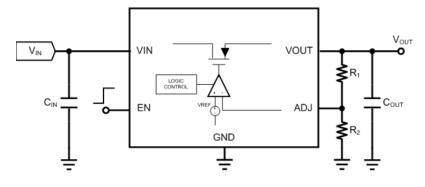


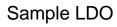


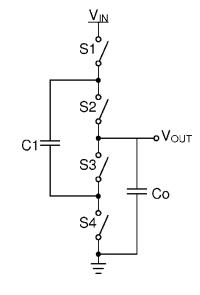


#### **Opportunities**

- Develop fine-grained and efficient on-the-fly power delivery solutions
  - Elimination of VR stages between source and point of consumption to improve response time and reduce losses
  - Increased integration of efficient low cost VR solutions to reduce droop
    - LDOs, SCVRs etc



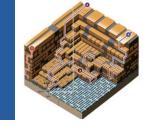






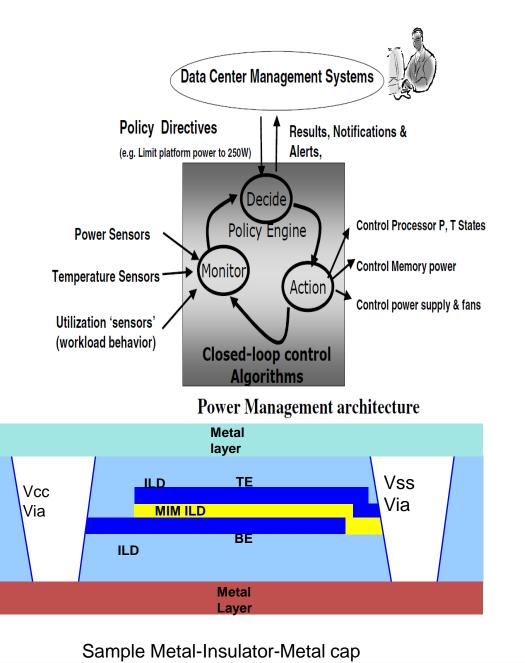






#### **Opportunities**

- **Develop fine-grained and efficient on**the-fly power delivery solutions
  - Active and sophisticated control systems that respond rapidly to current demands
  - High density die decoupling solutions
  - Deliver smooth and high fidelity power with minimal noise as voltage domains are power up and down





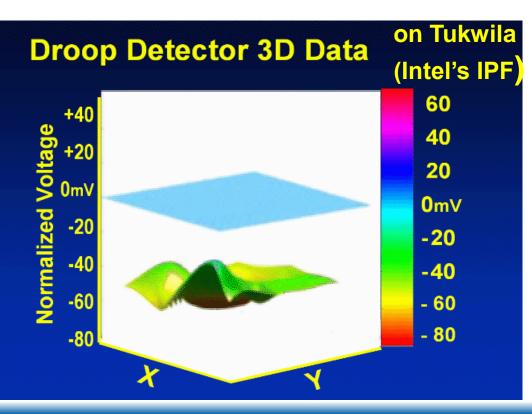


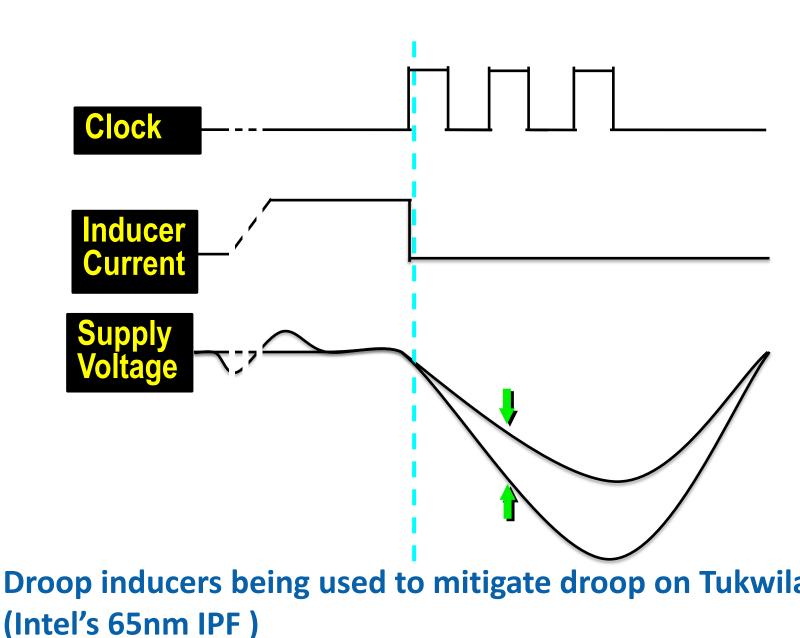


#### **Opportunities**

- Droop monitors to track and understand impact of droop
  - Droop detectors
  - Droop inducers

*Ref: ITC-2009 " Voltage Transient Detection and Induction for Debug and Test"* 







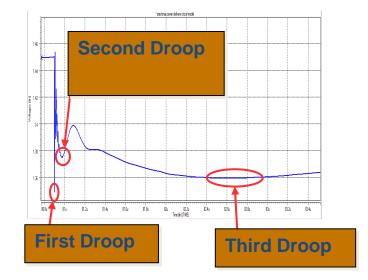


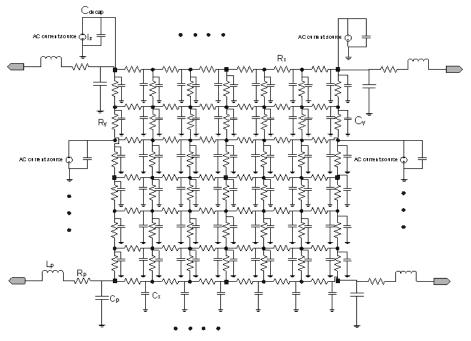


#### **Opportunities**

- Enhanced architectural solutions to proactively control and reduce high frequency droops
  - Instruction reordering
  - Instruction throttling

- Simulation strategies to accurately predict behavior in pre-Si
  - CAD tools to support capacity and efficiency
  - Emphasis on Package-die co-design/simulation





18

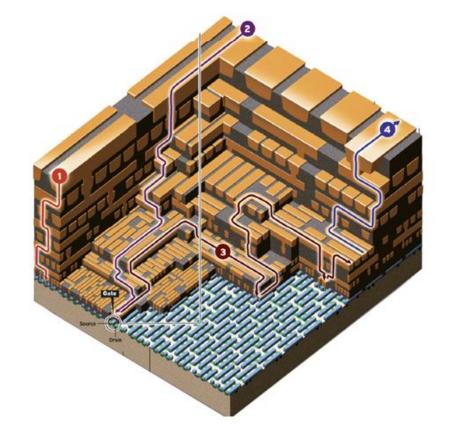




#### **Summary**

Entered era of bringing in intelligence to the power delivery system

- Look at increased integration of VRs to seamlessly support active and changing current demands on the chip
- Power management Dower delivery solution interactions
- Solutions to understand and alleviate
  - Impact of increased Cdyn range due to new instructions, higher performance cores, SIMD
- Creation of testbenches & tools to project and understand impact of degraded power delivery in pre-Si
- Lots of opportunities ahead!



19 (in





# BACKUP

